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| **Projekty schválené k dofinancování v roce 2021 v rámci EMPIR (7. výzva MŠMT) – kód 8B** | | | | | |
| **Český metrologický institut, Okružní 31, 638 00 Brno (IČ: 00177016)** | | | | | |
|  | **ID kód** | **Číslo projektu** | **Akronym projektu** | **Název projektu** | **Hlavní řešitel projektu** |
| 1. | **8B21001** | 20FUN02 | **POLight** | Pushing boundaries of nano-dimensional metrology by light | Mgr. Miroslav Valtr, Ph.D. |
| 2. | **8B21002** | 20FUN05 | **SEQUME** | Single- and entangled photon sources for quantum metrology | Dr. Ing. Marek Šmíd |
| 3. | **8B21003** | 20IND03 | **FutureCom** | RF Measurements for future communications applications | Ing. Martin Hudlička, Ph.D. |
| 4. | **8B21004** | 20IND05 | **QADeT** | Quantum sensors for metrology based on single-atom-like device technology | Dr. Ing. Marek Šmíd |
| 5. | **8B21005** | 20IND06 | **PROMETH2O** | Metrology for trace water in ultra-pure process gases | Dr. Ing. Radek Strnad, PhD. |
| 6. | **8B21006** | 20IND08 | **MetExSPM** | Traceability of localised functional properties of nanostructures with high speed scanning probe microscopy | Mgr. Petr Klapetek, Ph.D. |
| 7. | **8B21007** | 20IND09 | **PowerElec** | Metrology in manufacturing compound semiconductors for power electronics | Mgr. Petr Klapetek, Ph.D. |
| 8. | **8B21008** | 20IND12 | **Elena** | Electrical nanoscale metrology in industry | Mgr. Petr Klapetek, Ph.D. |
| 9. | **8B21009** | 20NET03 | **POLMO** | Support for a European Metrology Network on pollution monitoring | Ing. Petr Kovář |
| 10. | **8B21010** | 20NRM02 | **MFMET** | Establishing metrology standards in microfluidic devices | Mgr. Jan Geršl, Ph.D. |
| 11. | **8B21011** | 20SCP02 | **CEFTON** | Development of eye-tonometry in CEFTA countries | Ing. Václav Sedlák |
| 12. | **8B21012** | 20SIP02 | **FreeRelease** | Transfer of developed pre-selection and free release technology to decommissioning industries | Ing. Petr Kovář |